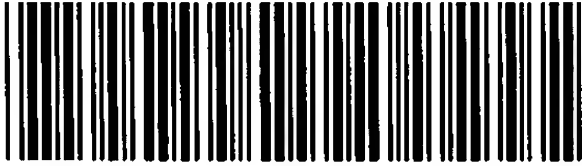


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/808,318	TAKANO ET AL.	
	Examiner	Art Unit	
	David B. Lugo	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	298, 300 308	11/12/2007	DL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	257, 298	11/12/2007	DL
375	300, 302	11/12/2007	DL
375	308	11/12/2007	DL
327/330, 352 455/114.3		11/12/2007	DL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East search	11/12/2007	DL